Obtain S-Parameter Data from the Probe Window

This document explains Measuring S parameters in PSpice using Probe measurements. It explains obtaining S parameter for a passive circuit (a band pass filter) and an active circuit (transistor circuit).
Introduction
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S parameter Theory
S-parameters measure the ratio of the incident and reflected signal. The incident signals are defined as $a_1$ and $a_2$. The reflected signals are defined as $b_1$ and $b_2$. The incident and reflected signals are related to voltages and currents at ports 1 and 2 by

$$a_1 = \frac{V_1 + Z_0 I_1}{2\sqrt{Z}}$$

$$a_2 = \frac{V_2 + Z_0 I_2}{2\sqrt{Z}}$$

$$b_1 = \frac{V_1 - Z_0 I_1}{2\sqrt{Z}}$$

$$b_2 = \frac{V_2 - Z_0 I_2}{2\sqrt{Z}}$$

The scattered waves are related to the incident waves by the following set of linear equations:

$$b_1 = S_{11} a_1 + S_{12} a_2$$

$$b_2 = S_{21} a_1 + S_{22} a_2$$

Or, in matrix form as;

$$\begin{bmatrix} b_1 \\ b_2 \end{bmatrix} = \begin{bmatrix} S_{11} & S_{12} \\ S_{21} & S_{22} \end{bmatrix} \begin{bmatrix} a_1 \\ a_2 \end{bmatrix}$$

The $S_{ij}$ coefficients are dimensionless ratios; for most applications, the characteristic impedance of the system, $Z_0$, is 50 ohms. $S_{11}$ is the input reflection ratio and is defined as the ratio of the input port reflected wave to the input incident wave. If the incident wave at the output, $a_2$, is set to zero, then the equations reduce to $b_1 = S_{11} a_1$ and $b_2 = S_{21} a_1$. Using the defining equations, this reduces to
\[ S_{11} = \frac{b_1}{a_1} = \frac{V_1 - Z_0 I_1}{V_1 + Z_0 I_1} = \frac{V_1 - Z_0 I_1}{V_1 + Z_0 I_1} = 2 \left( \frac{Z}{Z + Z_0} \right) - 1 \]  

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Where
V1/I1 is the input impedance Z.
S21 is the forward transmission ratio and is defined as the ratio b2/a1.

If the input and output load impedances of the circuit are the same, then S21 is the voltage measured at the output multiplied by 2. If the incident wave at the input is set to zero, then the equations reduce to

\[ b_1 = S_{12} a_2 \]
\[ b_2 = S_{22} a_2 \]

**Measuring S-Parameter Data from the PSpice Probe**

To make all of the necessary measurements, two sub schematics are required. These sub schematics, made in Allegro Design Entry CIS (Capture CIS), are shown in Figure.1 and Figure.2.

*Figure 1: XMITS circuit*
Sub Schematics
Create above circuits in Capture and create a hierarchical part for each. For the purpose of this article, these custom parts are named XMITS(Figure. 3) and REFLECTS(Figure. 4), respectively.

Sub Schematic for Transmission coefficients measurement, XMITS

The XMITS circuit shown in Figure 3 is used to measure the
- Forward transmission coefficient, S21
- Reverse transmission coefficients, S12

Since the output load matches the input load, the transmission coefficients are the output voltage multiplied by 2. The E device, E1, has a gain of 2. The port labeled CKT is used to connect to the external circuit. The port, STR,
is a hidden pin as shown in Figure 3. If it is left unconnected in a schematic, OrCAD Capture will generate a unique net. Alternatively, a specific net can be named for the connection by editing the PSpiceDefaultNet attribute value (see Figure 4) for the XMITS part instance; this way, the STR pin will have a known label (S21 in this case) when analyzing simulation results within the Probe window.

![Figure 4: Pin Properties for the XMITS part showing hidden STR pin](image)

**Sub schematic for Transmission coefficients measurement, REFLECTS**

![Figure 5: REFLECTS circuit and its hierarchical part](image)
The REFLECTS circuit shown in Figure 2 is used to measure the
- Input reflection coefficient, $S_{11}$
- Output reflection coefficient, $S_{22}$

The reflection coefficients are the input voltage multiplied by 2 minus AC unity. The E device, E1, has a gain of 2. As in the transmission coefficients measurement circuit, the interface pin labeled CKT is used to connect to the external circuit. The pin, SRE, is a hidden pin like STR described above, (see Figure 6). The REFLECTS symbol also has a DCbias property. On active circuits, the DC level can be set on voltage source, V1, by changing the DCbias property for the REFLECTS part instance in OrCAD Capture. By default, this property is set to zero.

![Image of REFLECTS symbol with CKT and S11](image.png)

**Figure 6: Pin Properties for the Reflects symbol showing hidden S_RE pin**

**Using the sub schematics**

The sub schematics can be used for both passive and active circuits. One can also create and use symbols from these sub schematic in design. Design example referred in this application note uses XMITS and REFLECTS symbols created from these sub schematics. See Creating and Editing Parts in the OrCAD Capture User's Guide for reference to creating hierarchical parts.

**Passive circuit implementation**

The circuit shown in Figure 7 is a fourth-order Butterworth bandpass filter with a center frequency of 250 MHZ. The first circuit measures $S_{11}$ and $S_{21}$. The second circuit measures $S_{12}$ and $S_{22}$. For simulation, the AC analysis settings are 500 linear points from 200 MHz to 350 MHZ. The results of the analysis are shown in Figure 8. Extract the attached Test_Case.zip to find the passive folder with this example.
Figure 7: Bandpass filter example

Figure 8: S11 and S21 for Filter Example
Active Circuit implementation

It is also possible to measure the s-parameters of an active circuit. To illustrate this, we have chosen to measure the s-parameters of the RF transistor, MRF5711/MC. Figure 9 shows the circuits for this example.

Figure 9: Transistor example

Figure 10: S11 and S22 magnitude and phase
Figure 11: S21 Magnitude and Phase

Figure 12: S12 Magnitude and Phase